

## Trench gate field-stop IGBT, M series 650 V, 20 A low loss

Datasheet - production data

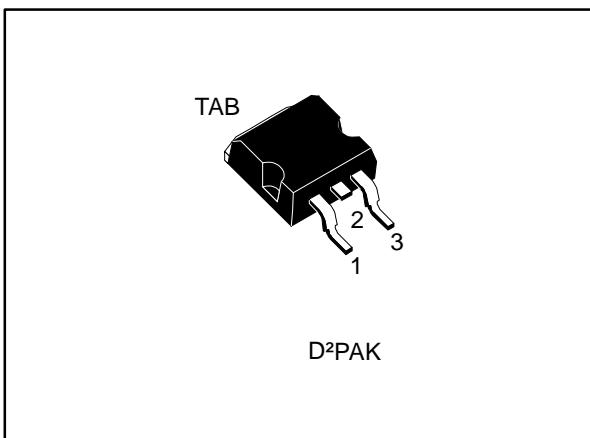
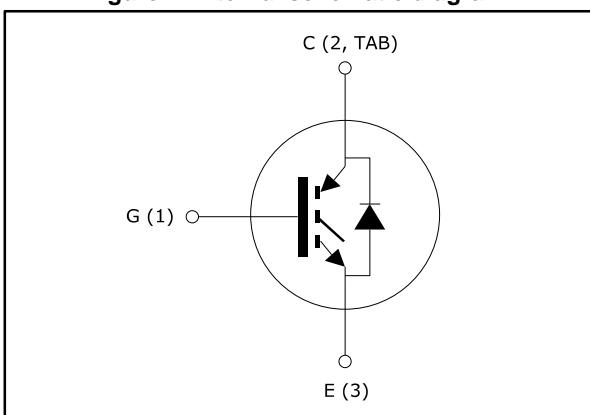


Figure 1: Internal schematic diagram



### Features

- High short-circuit withstand time
- $V_{CE(sat)} = 1.55 \text{ V}$  (typ.) @  $I_c = 20 \text{ A}$
- Tight parameters distribution
- Safer paralleling
- Low thermal resistance
- Soft and very fast recovery antiparallel diode

### Applications

- Motor control
- UPS
- PFC

### Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the M series IGBTs, which represent an optimal balance between inverter system performance and efficiency where low-loss and short-circuit functionality are essential. Furthermore, the positive  $V_{CE(sat)}$  temperature coefficient and tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGB20M65DF2	G20M65DF2	D²PAK	Tape and reel

**Contents**

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# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-emitter voltage ( $V_{GE} = 0$ )	650	V
$I_c$	Continuous collector current at $T_C = 25^\circ\text{C}$	40	A
$I_c$	Continuous collector current at $T_C = 100^\circ\text{C}$	20	A
$I_{CP}^{(1)}$	Pulsed collector current	80	A
$V_{GE}$	Gate-emitter voltage	$\pm 20$	V
$I_F$	Continuous forward current at $T_C = 25^\circ\text{C}$	40	A
$I_F$	Continuous forward current at $T_C = 100^\circ\text{C}$	20	A
$I_{FP}^{(1)}$	Pulsed forward current	80	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	166	W
$T_{STG}$	Storage temperature range	- 55 to 150	$^\circ\text{C}$
$T_J$	Operating junction temperature range	- 55 to 175	$^\circ\text{C}$

**Notes:**

(1)Pulse width limited by maximum junction temperature.

**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance junction-case IGBT	0.9	$^\circ\text{C}/\text{W}$
$R_{thJC}$	Thermal resistance junction-case diode	2.08	$^\circ\text{C}/\text{W}$
$R_{thJA}$	Thermal resistance junction-ambient	62.5	$^\circ\text{C}/\text{W}$

## 2 Electrical characteristics

$T_C = 25^\circ\text{C}$  unless otherwise specified

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}$ , $I_C = 250 \mu\text{A}$	650			V
$V_{CE(\text{sat})}$	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}$ , $I_C = 20 \text{ A}$		1.55	2.0	V
		$V_{GE} = 15 \text{ V}$ , $I_C = 20 \text{ A}$ , $T_J = 125^\circ\text{C}$		1.95		
		$V_{GE} = 15 \text{ V}$ , $I_C = 20 \text{ A}$ , $T_J = 175^\circ\text{C}$		2.1		
$V_F$	Forward on-voltage	$I_F = 20 \text{ A}$		1.85		V
		$I_F = 20 \text{ A}$ , $T_J = 125^\circ\text{C}$		1.65		
		$I_F = 20 \text{ A}$ , $T_J = 175^\circ\text{C}$		1.55		
$V_{GE(\text{th})}$	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 500 \mu\text{A}$	5	6	7	V
$I_{CES}$	Collector cut-off current	$V_{GE} = 0 \text{ V}$ , $V_{CE} = 650 \text{ V}$			25	$\mu\text{A}$
$I_{GES}$	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}$ , $V_{GE} = \pm 20 \text{ V}$			250	$\mu\text{A}$

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{ies}$	Input capacitance	$V_{CE} = 25 \text{ V}$ , $f = 1 \text{ MHz}$ , $V_{GE} = 0 \text{ V}$	-	1688	-	pF
$C_{oes}$	Output capacitance		-	95	-	
$C_{res}$	Reverse transfer capacitance		-	35	-	
$Q_g$	Total gate charge	$V_{CC} = 520 \text{ V}$ , $I_C = 20 \text{ A}$ , $V_{GE} = 15 \text{ V}$ (see <a href="#">Figure 30: "Gate charge test circuit"</a> )	-	63	-	nC
$Q_{ge}$	Gate-emitter charge		-	15	-	
$Q_{gc}$	Gate-collector charge		-	26	-	

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 20 \text{ A}, V_{GE} = 15 \text{ V}, R_G = 12 \Omega$ (see <a href="#">Figure 29: "Test circuit for inductive load switching"</a> )		26	-	ns
$t_r$	Current rise time			10.8	-	ns
$(di/dt)_{on}$	Turn-on current slope			1409	-	A/ $\mu\text{s}$
$t_{d(off)}$	Turn-off-delay time			108	-	ns
$t_f$	Current fall time			65	-	ns
$E_{on(1)}$	Turn-on switching energy			0.14	-	mJ
$E_{off(2)}$	Turn-off switching energy			0.56	-	mJ
$E_{ts}$	Total switching energy			0.7	-	mJ
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 20 \text{ A}, V_{GE} = 15 \text{ V}, R_G = 12 \Omega, T_J = 175 \text{ }^\circ\text{C}$ (see <a href="#">Figure 29: "Test circuit for inductive load switching"</a> )		28.4	-	ns
$t_r$	Current rise time			11.2	-	ns
$(di/dt)_{on}$	Turn-on current slope			1393	-	A/ $\mu\text{s}$
$t_{d(off)}$	Turn-off-delay time			107	-	ns
$t_f$	Current fall time			145	-	ns
$E_{on(1)}$	Turn-on switching energy			0.3	-	mJ
$E_{off(2)}$	Turn-off switching energy			0.85	-	mJ
$E_{ts}$	Total switching losses			1.15	-	mJ
$t_{sc}$	Short-circuit withstand time	$V_{CC} = 400 \text{ V}, V_{GE} = 13 \text{ V}, T_{Jstart} = 150 \text{ }^\circ\text{C}$	10		-	$\mu\text{s}$
		$V_{CC} = 400 \text{ V}, V_{GE} = 15 \text{ V}, T_{Jstart} = 150 \text{ }^\circ\text{C}$	6		-	

**Notes:**

(1) Including the reverse recovery of the diode.

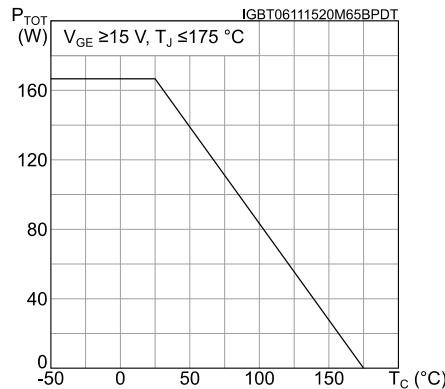
(2) Including the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

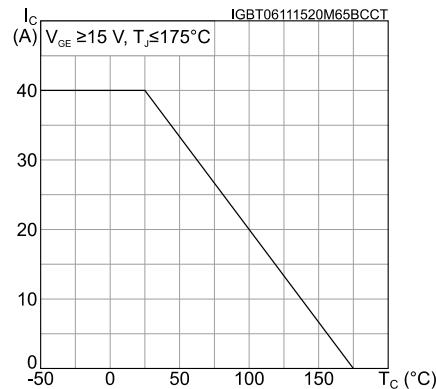
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{rr}$	Reverse recovery time	$I_F = 20 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}$ (see <i>Figure 29: "Test circuit for inductive load switching"</i> ) $di/dt = 1000 \text{ A}/\mu\text{s}$	-	166		ns
$Q_{rr}$	Reverse recovery charge		-	690		nC
$I_{rrm}$	Reverse recovery current		-	13.2		A
$dI_{rr}/dt$	Peak rate of fall of reverse recovery current during $t_b$		-	769		A/ $\mu\text{s}$
$E_{rr}$	Reverse recovery energy		-	81		$\mu\text{J}$
$t_{rr}$	Reverse recovery time	$I_F = 20 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}$ $T_J = 175 \text{ }^\circ\text{C}$ (see <i>Figure 29: "Test circuit for inductive load switching"</i> ) $di/dt = 1000 \text{ A}/\mu\text{s}$	-	281		ns
$Q_{rr}$	Reverse recovery charge		-	2010		nC
$I_{rrm}$	Reverse recovery current		-	19.6		A
$dI_{rr}/dt$	Peak rate of fall of reverse recovery current during $t_b$		-	370		A/ $\mu\text{s}$
$E_{rr}$	Reverse recovery energy		-	215		$\mu\text{J}$

## 2.1 Electrical characteristics(curves)

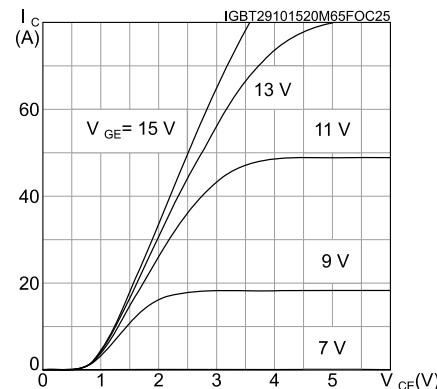
**Figure 2: Power dissipation vs. case temperature**



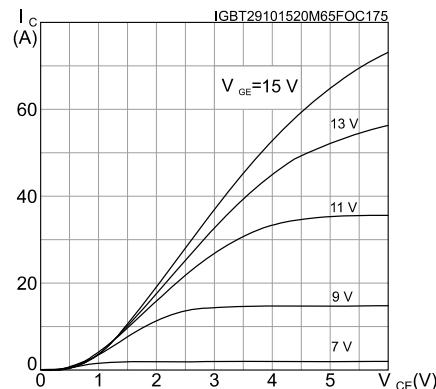
**Figure 3: Collector current vs. case temperature**



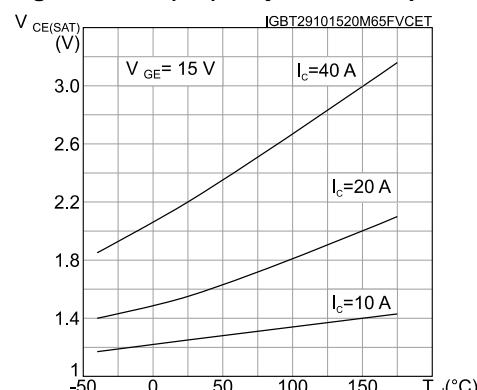
**Figure 4: Output characteristics ( $T_J = 25$  °C)**



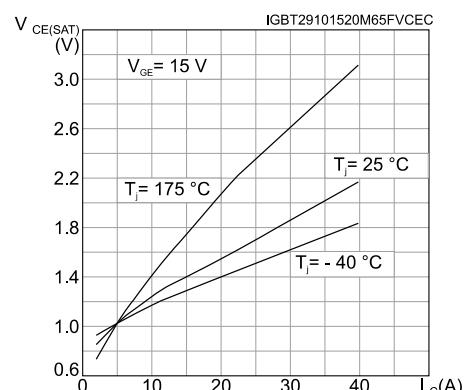
**Figure 5: Output characteristics ( $T_J = 175$  °C)**

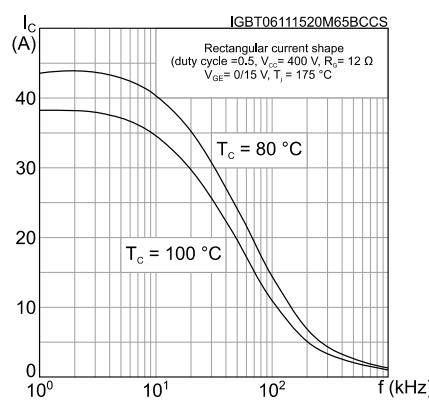
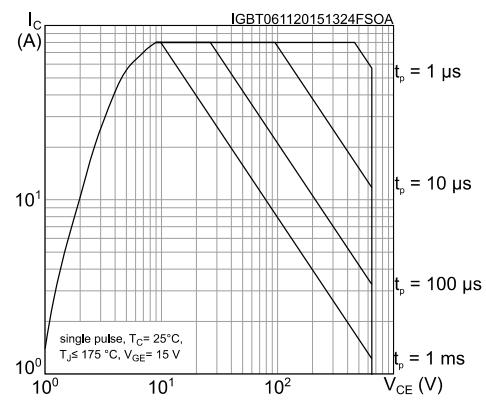
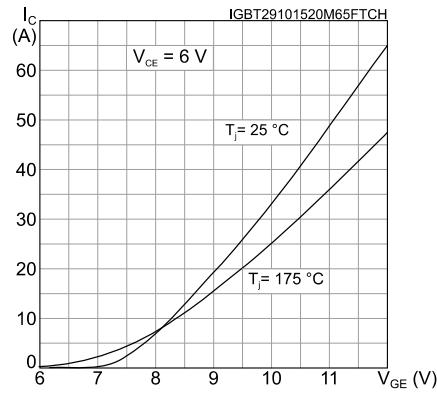
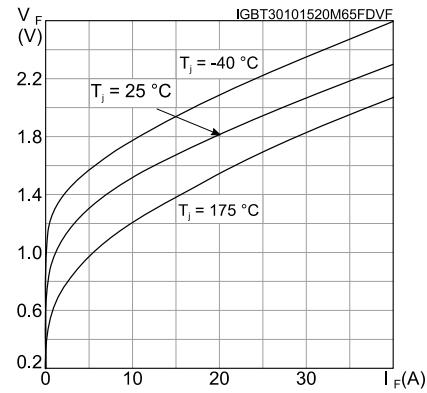
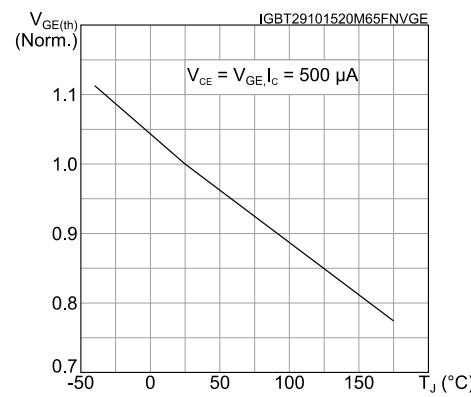
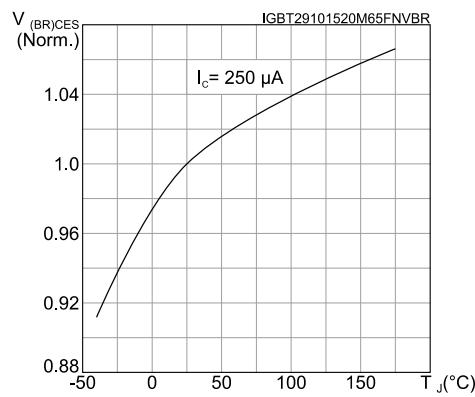


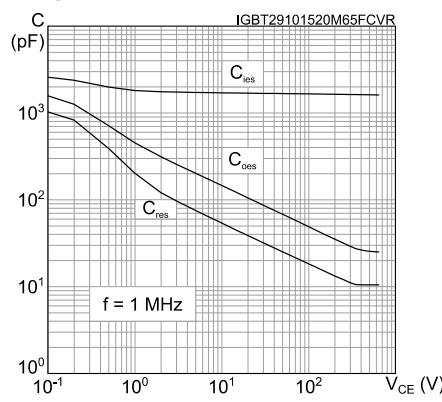
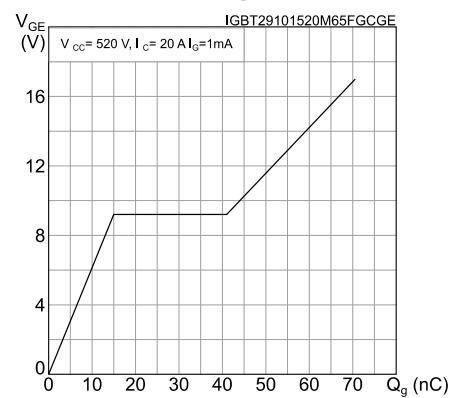
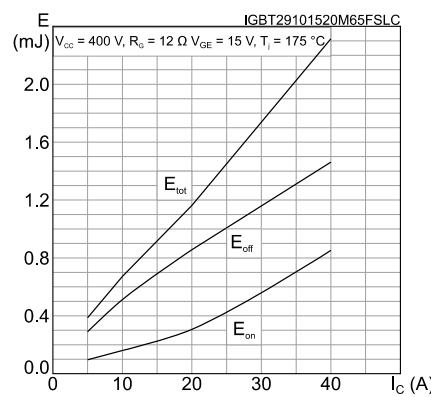
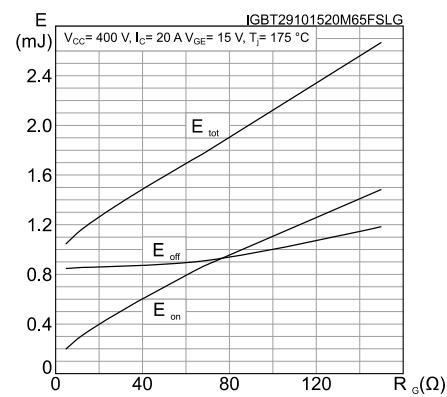
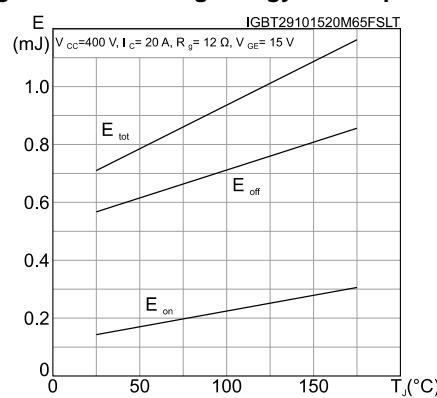
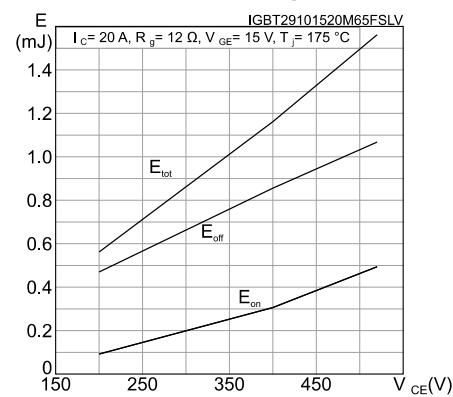
**Figure 6:  $V_{CE(sat)}$  vs. junction temperature**



**Figure 7:  $V_{CE(sat)}$  vs. collector current**



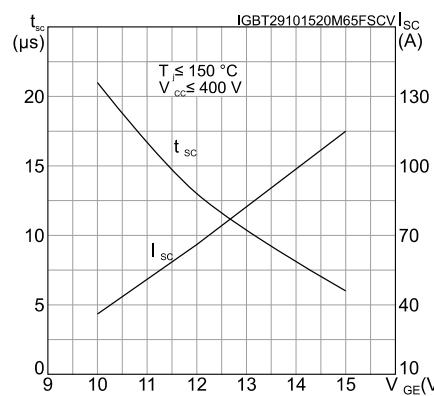
**Figure 8: Collector current vs. switching frequency****Figure 9: Forward bias safe operating area****Figure 10: Transfer characteristics****Figure 11: Diode VF vs. forward current****Figure 12: Normalized VGE(th) vs. junction temperature****Figure 13: Normalized V(BR)CES vs. junction temperature**

**Figure 14: Capacitance variations****Figure 15: Gate charge vs. gate-emitter voltage****Figure 16: Switching energy vs. collector current****Figure 17: Switching energy vs. gate resistance****Figure 18: Switching energy vs. temperature****Figure 19: Switching energy vs. collector-emitter voltage**

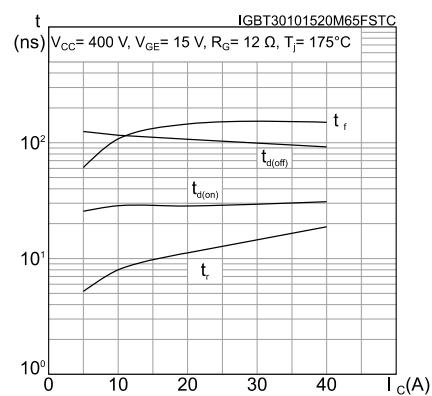
## Electrical characteristics

**STGB20M65DF2**

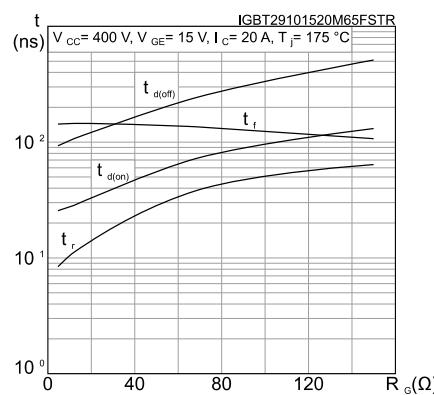
**Figure 20: Short-circuit time and current vs. V<sub>GE</sub>**



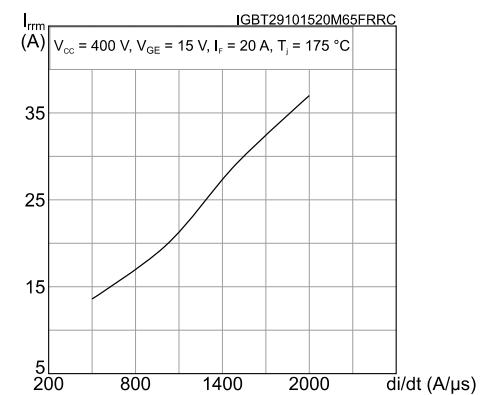
**Figure 21: Switching times vs. collector current**



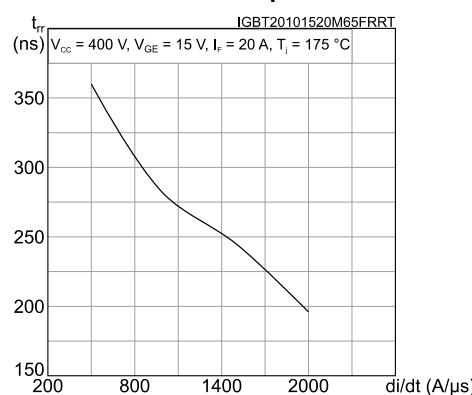
**Figure 22: Switching times vs. gate resistance**



**Figure 23: Reverse recovery current vs. diode current slope**



**Figure 24: Reverse recovery time vs. diode current slope**



**Figure 25: Reverse recovery charge vs. diode current slope**

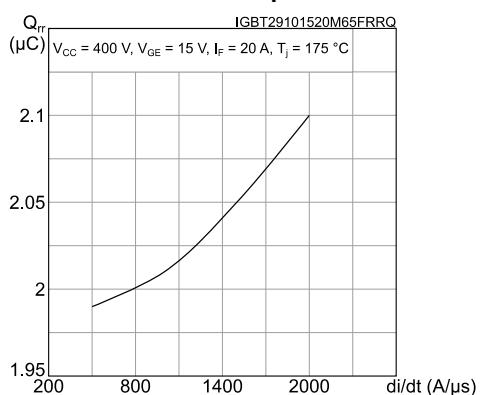


Figure 26: Reverse recovery energy vs. diode current slope

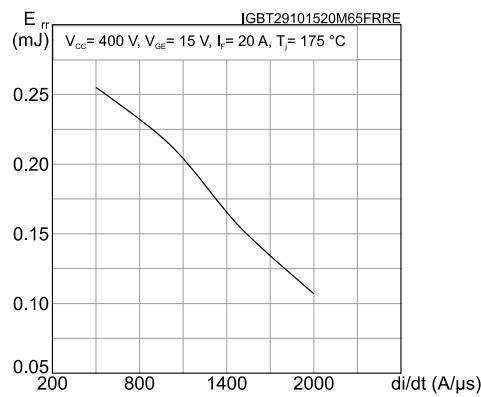


Figure 27: Thermal impedance for IGBT

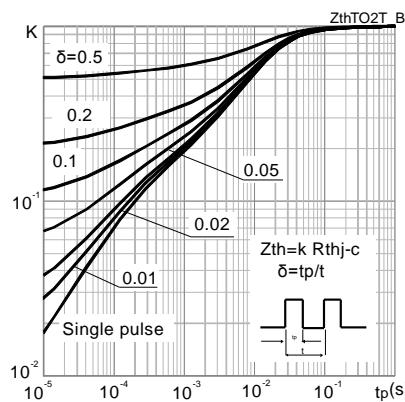
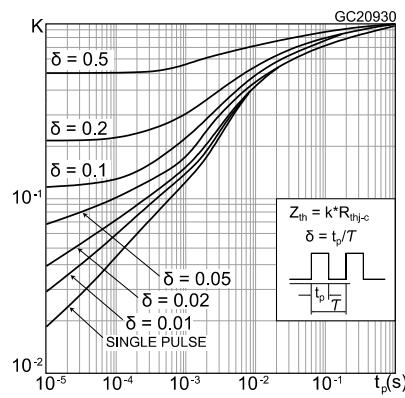
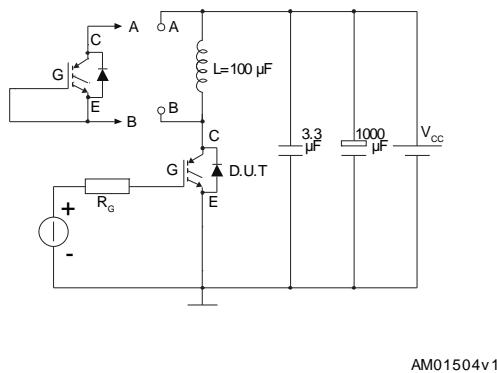


Figure 28: Thermal impedance for diode

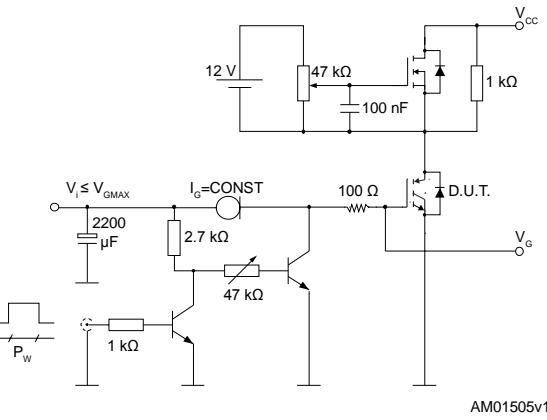


### 3 Test circuits

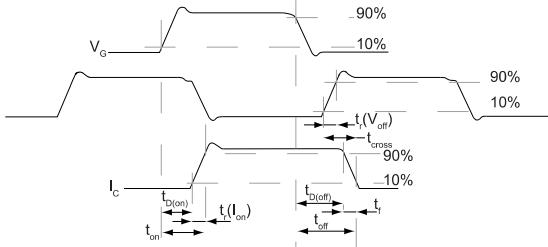
**Figure 29: Test circuit for inductive load switching**



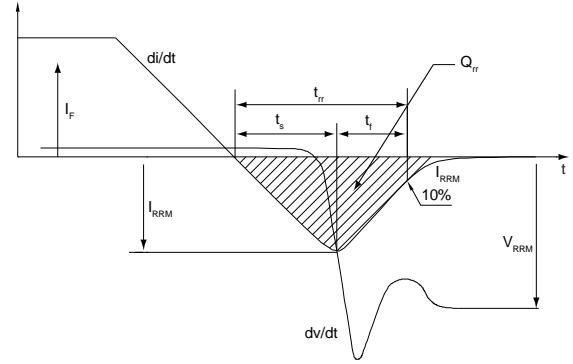
**Figure 30: Gate charge test circuit**



**Figure 31: Switching waveform**



**Figure 32: Diode reverse recovery waveform**



## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

### 4.1 D<sup>2</sup>PAK (TO-263) type A package information

Figure 33: D<sup>2</sup>PAK (TO-263) type A package outline

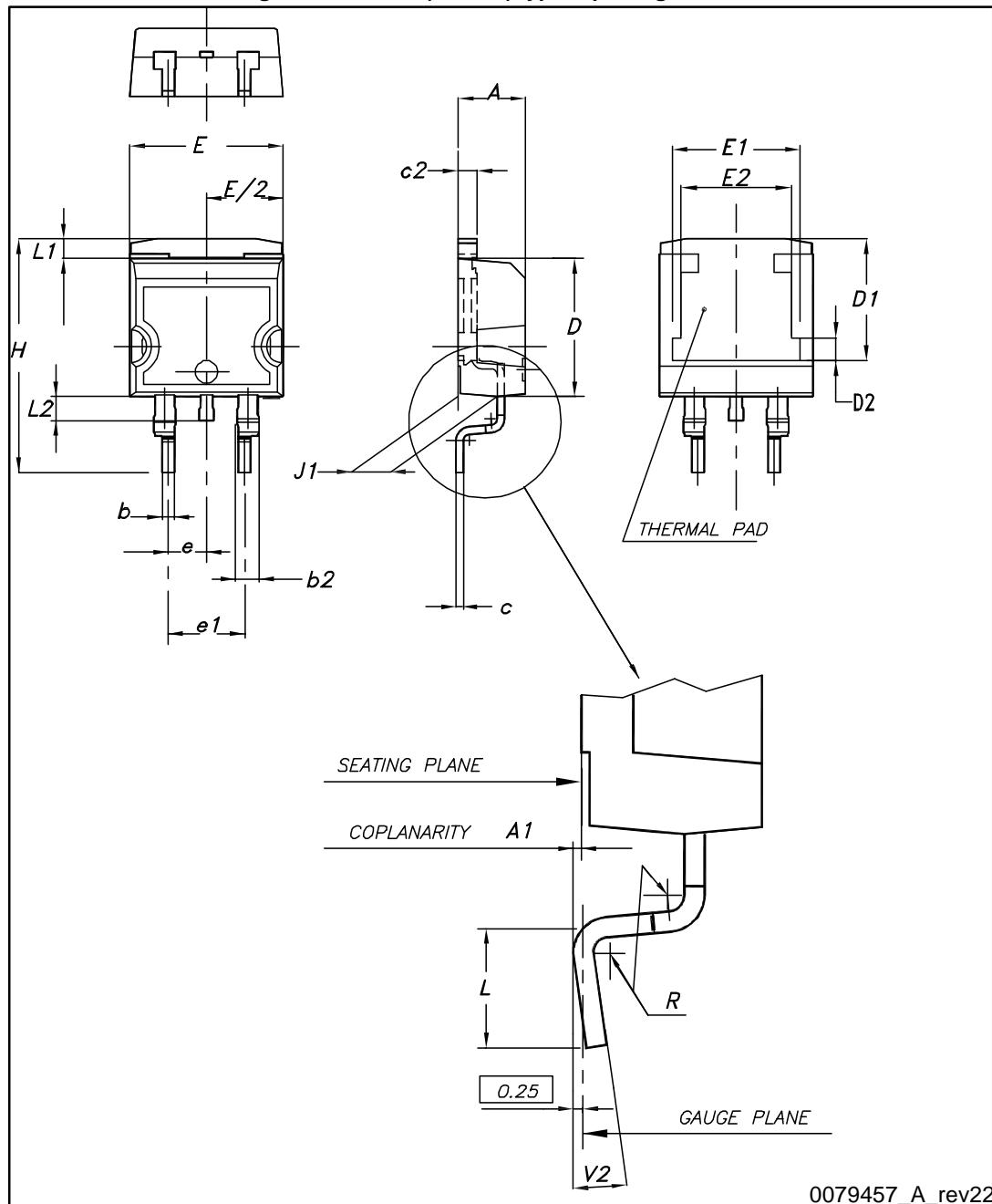
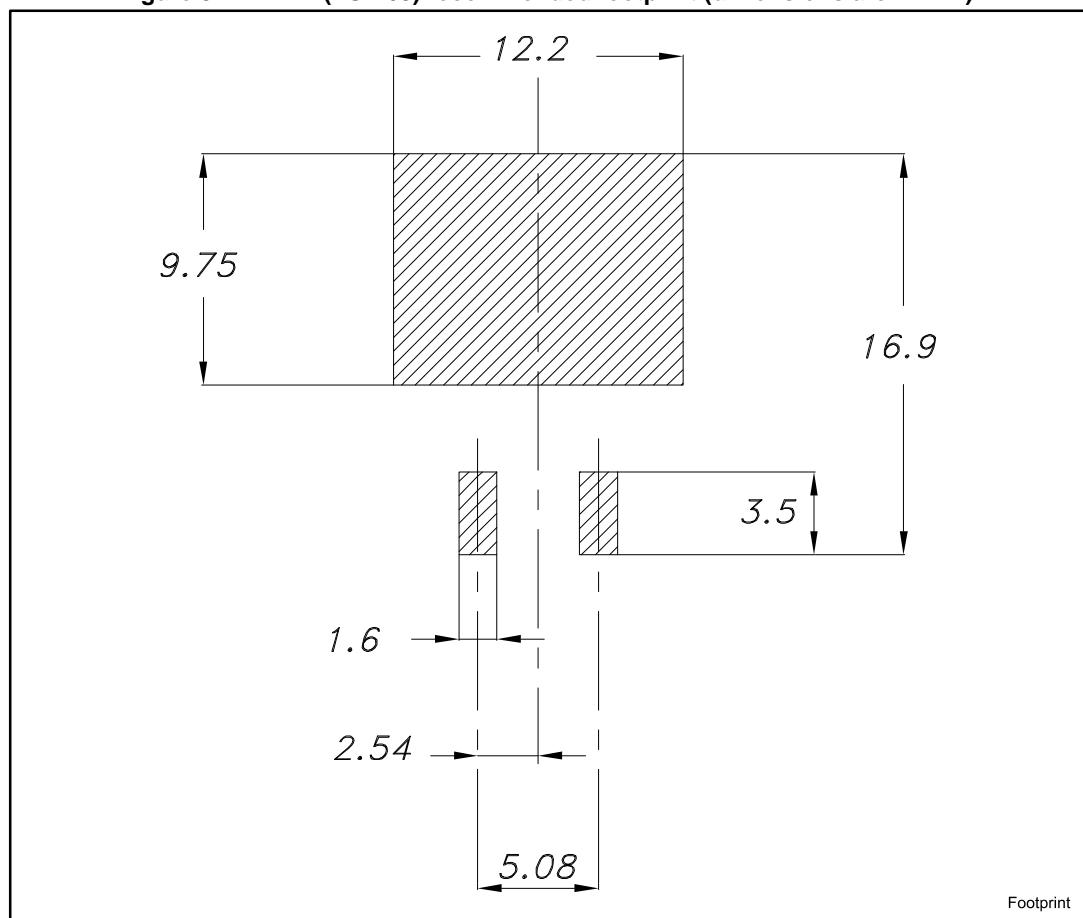


Table 8: D<sup>2</sup>PAK (TO-263) type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50	7.75	8.00
D2	1.10	1.30	1.50
E	10		10.40
E1	8.50	8.70	8.90
E2	6.85	7.05	7.25
e		2.54	
e1	4.88		5.28
H	15		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.4	
V2	0°		8°

Figure 34: D<sup>2</sup>PAK (TO-263) recommended footprint (dimensions are in mm)

## 4.2 Packing information

Figure 35: Tape outline

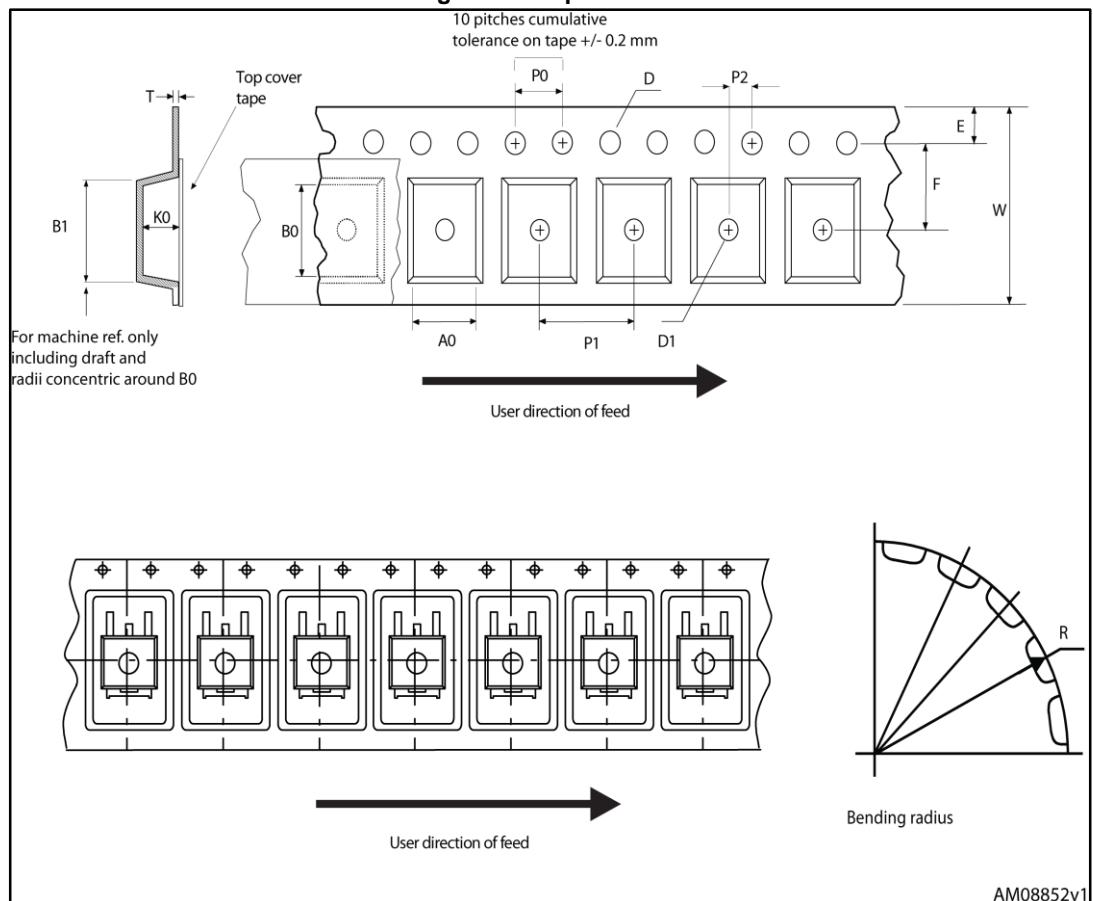
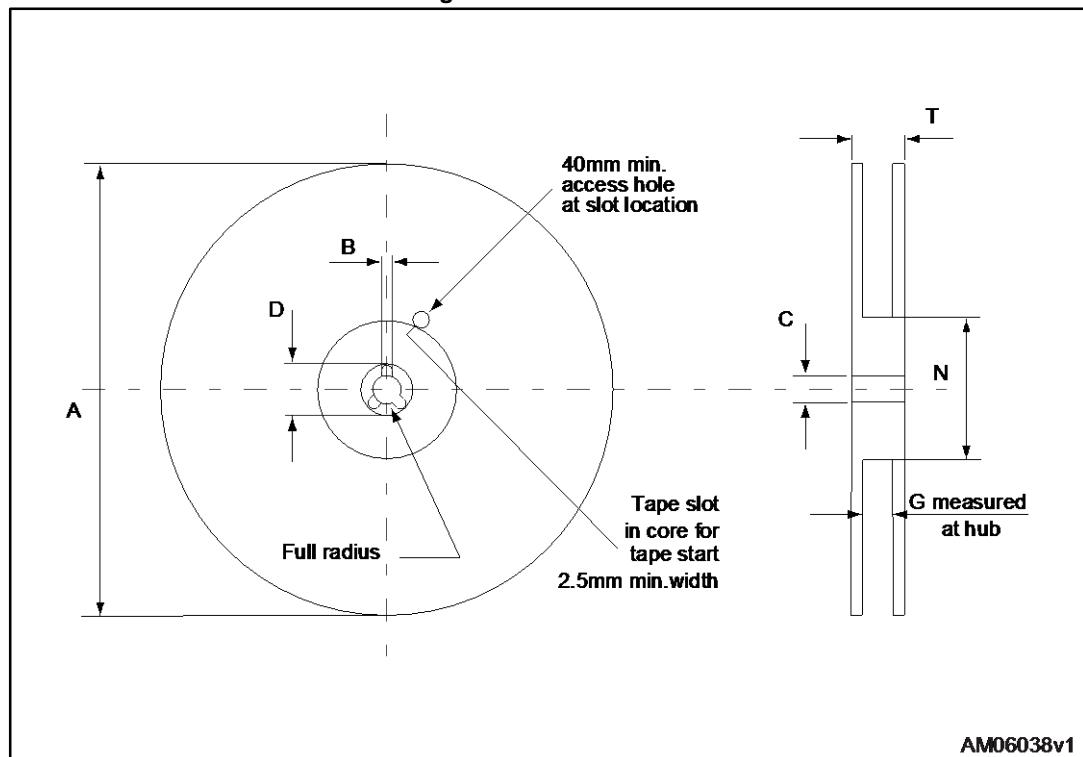


Figure 36: Reel outline

Table 9: D<sup>2</sup>PAK tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base quantity		1000
P2	1.9	2.1	Bulk quantity		1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

## 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
05-Nov-2015	1	First release.
14-Apr-2016	2	Updated <a href="#">Figure 13: "Normalized V(BR)CES vs. junction temperature"</a> . Minor text changes.

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